

Search Notes

Application/Control No.

10/642,766

Examiner

John R. Hardee

Applicant(s)/Patent under
Reexamination

WENG, CHUAN

Art Unit

1751

SEARCHED

Class	Subclass	Date	Examiner
252	67	1/28/2005	JRH
	68	<i>h</i>	<i>h</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STN	1/28/2005	JRH
EAST text and image	<i>h</i>	<i>h</i>